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| Application Number | | 10677849 |
| Filing Date | | 2003-10-02 |
| First Named Inventor | Yoshiyuki Abe | |
| Art Unit | 1796 | |
| Examiner Name | Mark T. Kopeck | |
| Attorney Docket Number | KAM 20.660 | |

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| /MK/ | 1 | 20030218153 | | 2003-11-27 | Yoshiyuki Abe | |

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| /MK/ | 3 | 1174390 | EP | | 2002-01-23 | JAPAN SCIENCE AND TECHNOLOGY CORPORATION | | <input type="checkbox"/> |

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| /MK/ | 2 | A.E. DELAHAY, et al., "Transparent and semitransparent conducting film deposition by reactive-environment, hollow cathod sputtering", Journal of Vacuum Science and Technology A, Vacuum, Surfaces and Films, June 28, 2005, pg(s) 1215-1220, Vol. 23, no. 4, American Institute of Physics, New York, NY U.S. | <input type="checkbox"/> |
| /MK/ | 3 | I. SAFI, et al., "The properties of reactively-sputtered, stoichiometry-controlled and optimum-conductivity transparent indium oxide films as a function of their titanium, aluminum and zinc content; comparisons with the use of tin as a dopant", April 1999, vol. 343-344, pg(s) 115-118, Dept. of Physics, Loughborough University, Loughborough, UK. | <input type="checkbox"/> |
| /MK/ | 4 | G. CAMPET, et al., "The electronic effect of T14+, ZR4+ and GE4+ dopings upon the physical properties of IN203 and SN-doped IN203 ceramics: application to new highly-transparent conductive electrodes", June 20, 1993, pg(s) 285-289, vol. B19, no. 3, Lausanne, CH | <input type="checkbox"/> |
| /MK/ | 5 | E. HUSENOV, et al., "IR-detectors based on In203-anode oxide-CdxHg1-xTe" International Journal of Infrared and Millimeter Waves, September 2002, vol. 23, no. 9, pg(s) 1337-1345, Plenum Publishing Corporation, U.S. | <input type="checkbox"/> |
| /MK/ | 6 | F.L. SUTHERLAND, et al "Preparation and properties of transparent conducting films of ZnO and In203", September 1, 1988, pg.(s) 172-175, vol. 3, no. 3, Chemtronics, Butterworth Scientific Ltd., Guildford, GB | <input type="checkbox"/> |

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